

# **Status of OTIS Outer Tracker Time Information System**

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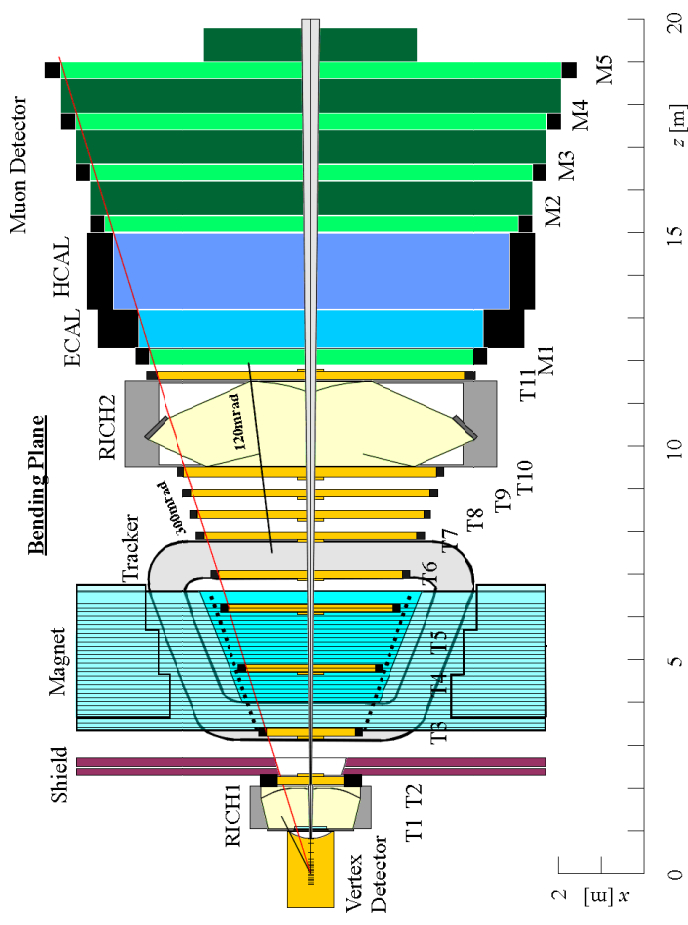
# LHCb at Cern



Cern



LHCb



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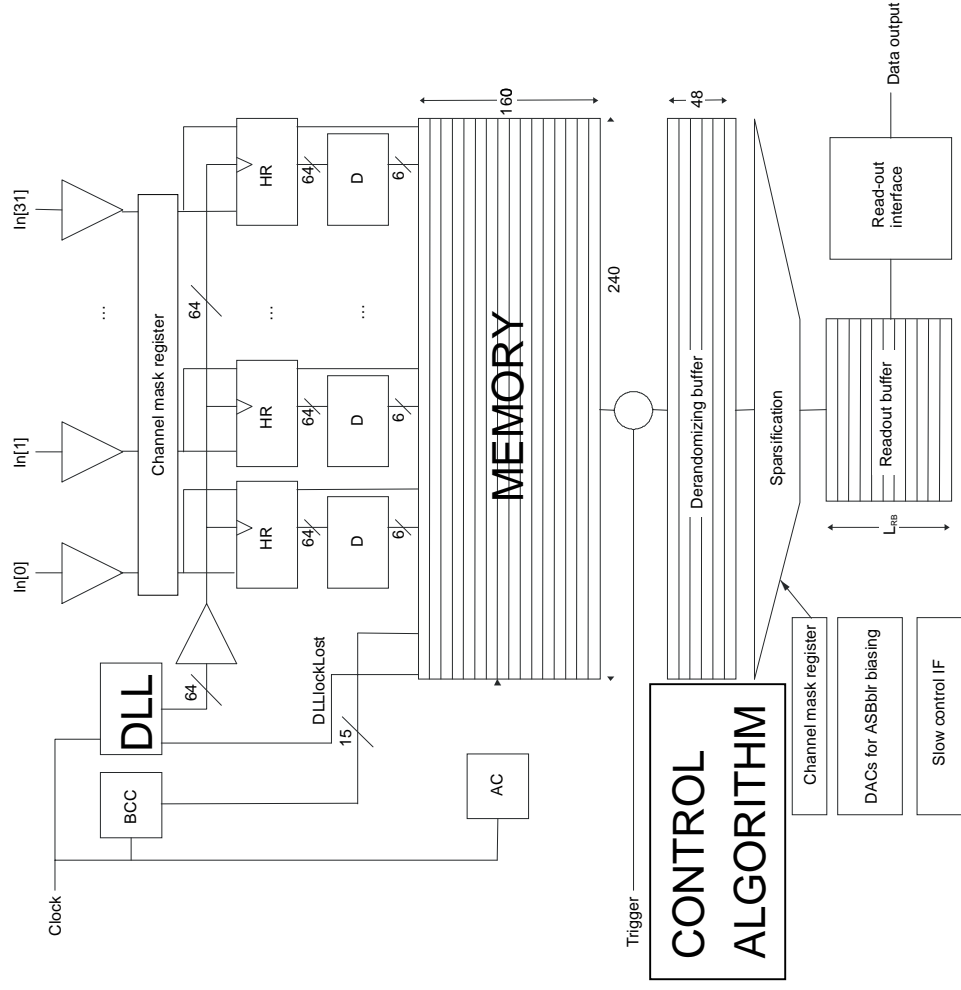
# OTIS TDC



## Outer Tracker Time Information System

- 3.250 OTIS-TDCs with 32 channels each
- 4 OTIS TDCs are connected to one GOL fast serializer  $\Rightarrow$  one fibre per 128 channels
- Radiation hard layout 0.25  $\mu\text{m}$
- DLL fine time resolution 6 bit
- Dual Ported Memory with 1.2 Gb/s, 240 bit width  $\Rightarrow$  low power design
- Synchronous clock driven readout

# LHCb OTIS TDC



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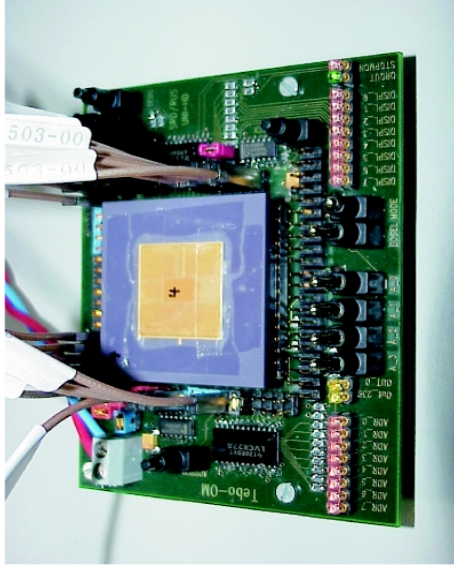
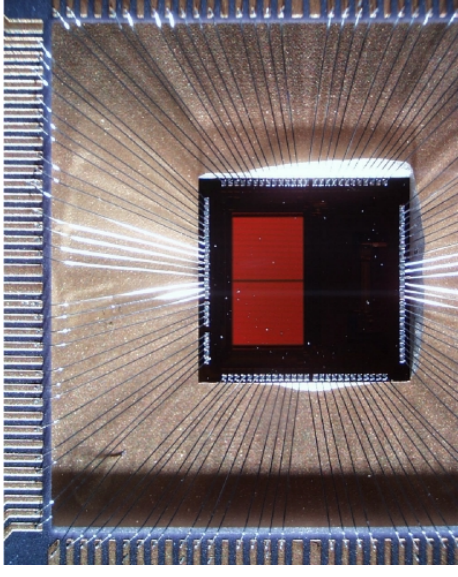
# Delay Locked Loop



Test chip for MEMORY and DLL with MUX: OTISMEM1.0, submitted February 2001

Chip OTISMEM1.0 received and tested:  
Preliminary results available

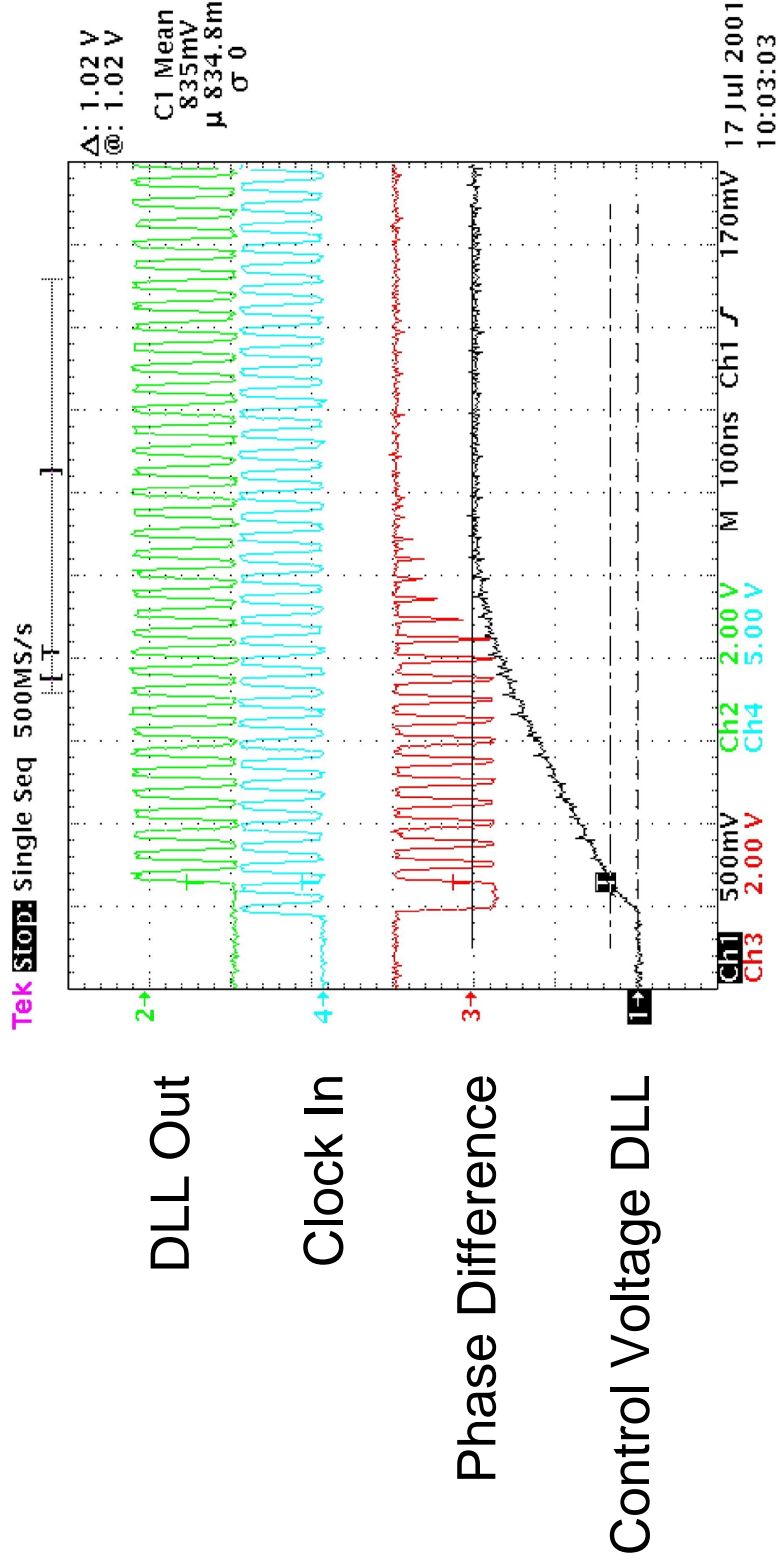
- 2nd DLL prototype, contains:
  - Delay chain with 32 stages 2 taps each
  - Mean delay per tap  $25\text{ns}/64 = 390\text{ps}$
  - Currently Hit Register for only one channel with 64 bit multiplexed to 4 pads



# DLL Lock Time



- Lock Time is below  $1\mu\text{s}$

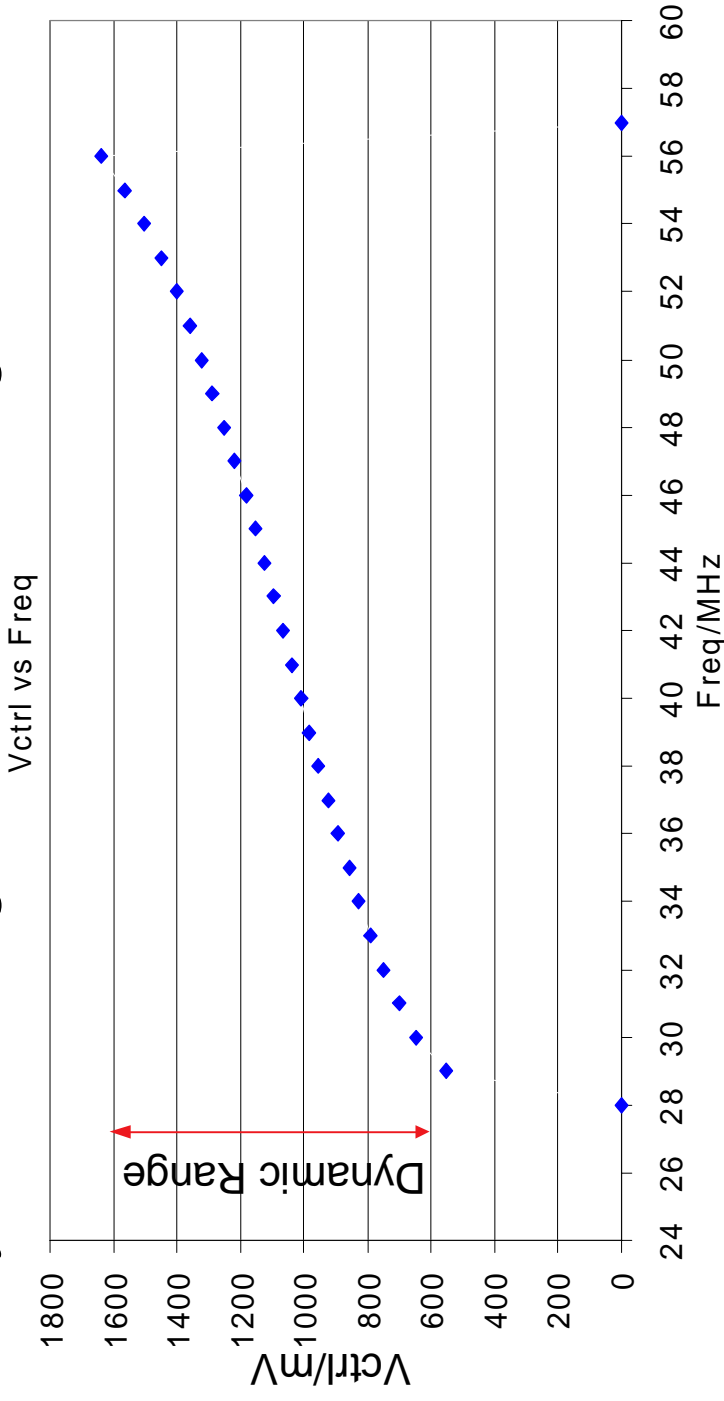


# DLL Lock Range



- Lock Range = 29...56MHz at 300K
- simulated Lock Range 30...50MHz (Within an 10% error)
- Spec is 30...50MHz at 300K → OK !!!

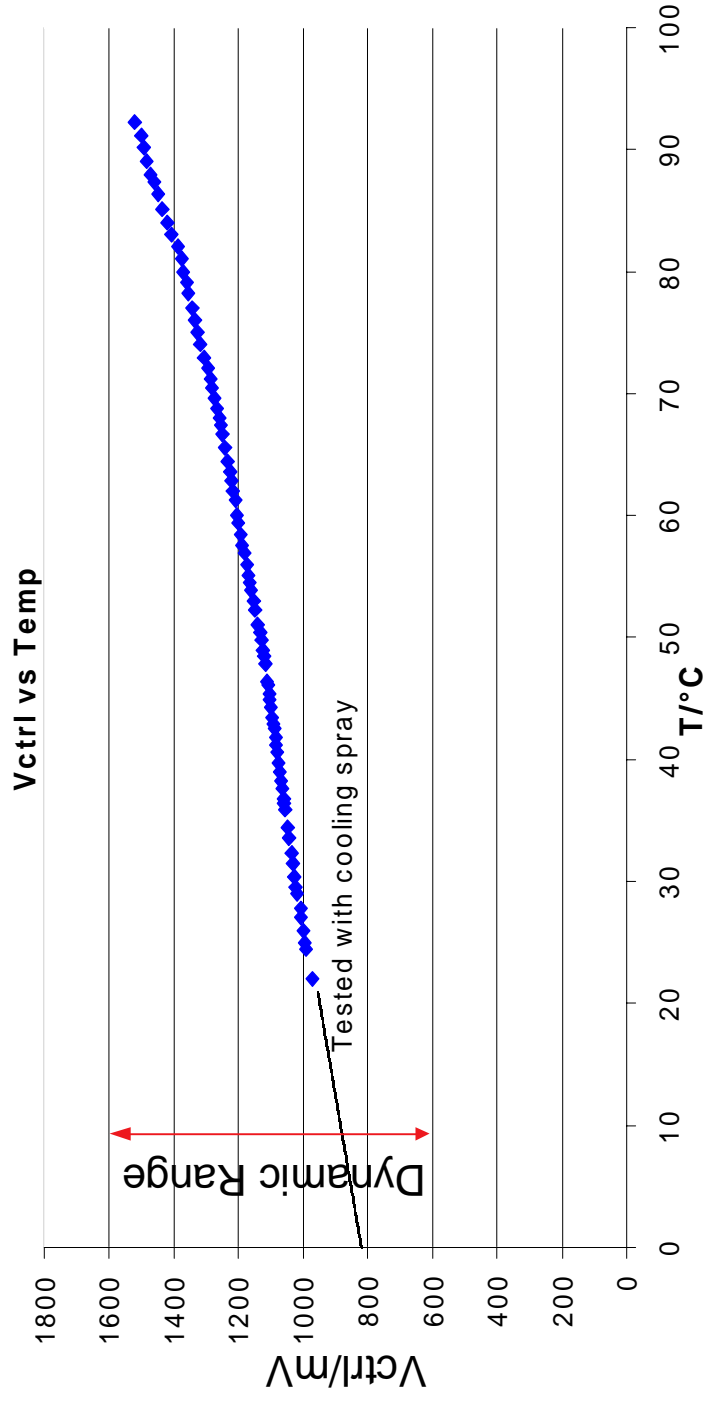
## ■ Dynamic Range of Control Voltage 1V



# DLL Temperature Range



- Measurement of Temperature Range
- Control Voltage inside Dynamic Range for all tested Temperatures at 40 MHz

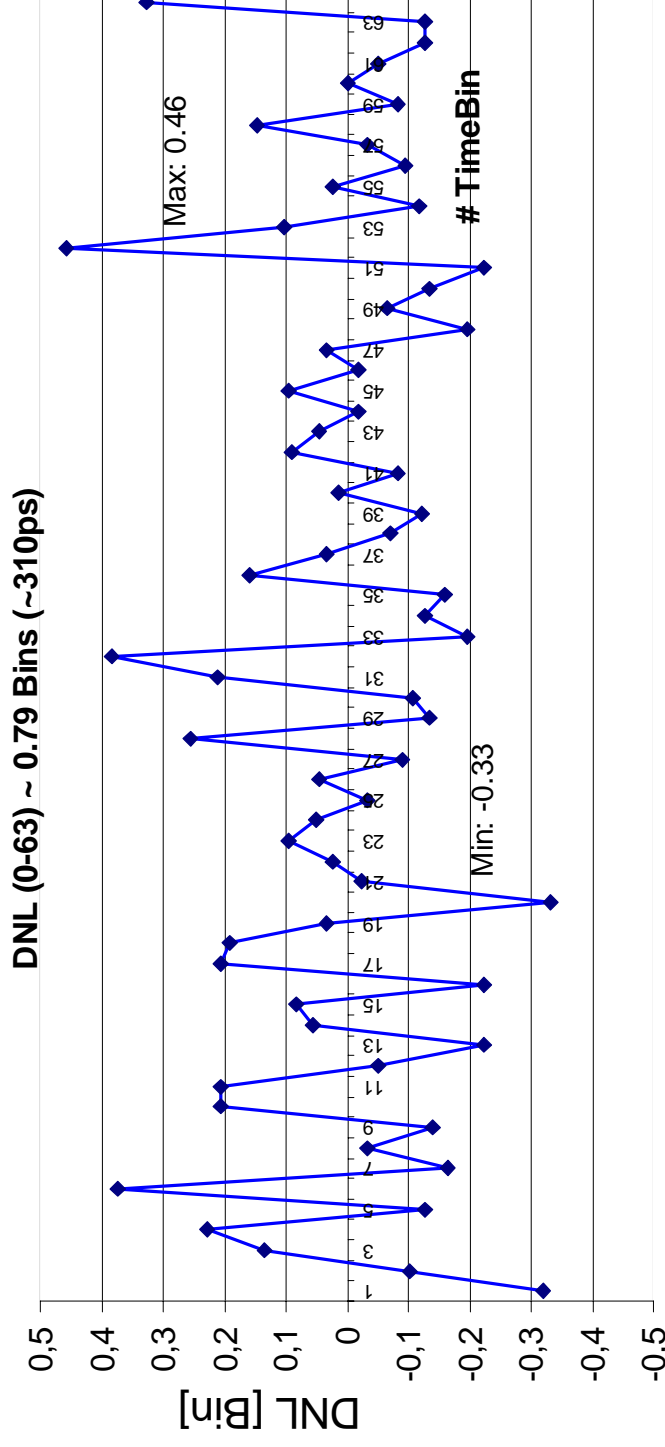




# DLL Differential Non Linearity

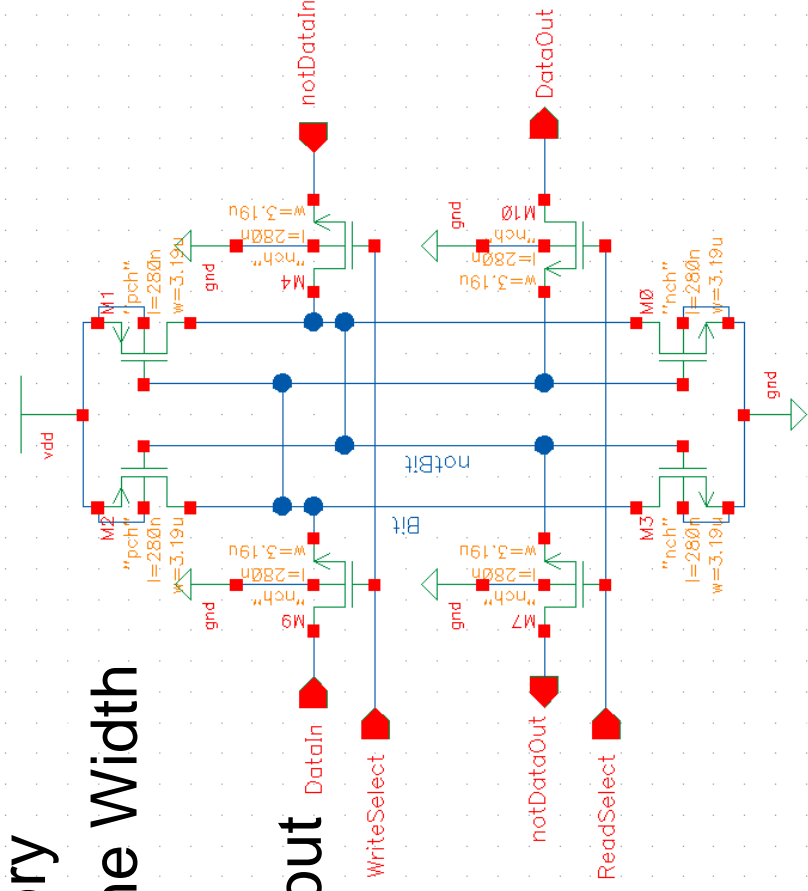


- Differential Non-Linearity (DNL) preliminary:
    - 0.79bins (~310ps) at 40MHz
    - Influence of MEMORY switching on DLL not tested
    - Influence of test chip specific MUX on DLL⇒Guard Ring
- cut DNL #Bin (40MHz, Duty 50:50, Events/MuxAdr =10.000)



# OTIS MEMORY

- Implemented on OTIS MEM1.0
- Dual Ported Memory
- 240 bit total Pipeline Width
- 164 rows long
- Radiation hard layout
- Low power design



# MEMORY Timing



Symbol	Parameter	Simulation		Test chip		Unit
		Best	Worst	Best	Worst	
$t_{AVRH}$	address valid to read enable high	$\geq 1.5$	$\geq 3$	$\geq -0.3$	$\geq -0.3$	ns
$t_{RLAX}$	read enable low to address transition	$\geq 2.5$	$\geq 5$	$\geq -0.6$	$\geq -0.3$	ns
$t_{RHRL}$	read enable high to read enable low	$\geq 4$	$\geq 8$	$\geq 1.6$	$\geq 2.1$	ns
$t_{RLRH}$	read enable low to read enable high	$\geq 8$	$\geq 15$	$\geq 5.9$	$\geq 6.7$	ns
$t_{RLDX}$	read enable low to data transition	$= 1$	$= 2$	$= 1.3$	$= 1.6$	ns
$t_{RLDV}$	read enable low to data valid	$= 3.5$	$= 7$	$= 4.7$	$= 5.1$	ns
$t_{DWWL}$	data valid to write enable low	$\geq 1.5$	$\geq 3$	$\geq 0.4$	$\geq 0.5$	ns
$t_{WLDX}$	write enable low to data transition	$\geq 1.5$	$\geq 3$	$\geq 1.5$	$\geq 1.6$	ns
$t_{AWWL}$	address valid to write enable low	$\geq 1.5$	$\geq 3$	$\geq 2.7$	$\geq 3.0$	ns
$t_{WLAX}$	write enable low to address transition	$\geq 4.5$	$\geq 9$	$\geq 2.7$	$\geq 3.0$	ns
$t_{WHWL}$	write enable high to write enable low	$\geq 4$	$\geq 7$	$\geq 2.8$	$\geq 3.2$	ns
$t_{WLWH}$	write enable low to write enable high	$\geq 8$	$\geq 16$	$\geq x < 5$	$\geq x < 5$	ns

# OTIS CONTROL ALGORITHM



- Implementation of control elements in Verilog exists
- Simulation of:
  - Verilog Code exists
  - FPGA Code exists
- Tests on FPGA are running

The FPGA is used for verification of the OTIS CONTROL ALGORITHM.

# Implemented Elements



- Bunch crossing Counter
- Pipeline Control
- Copy to Derandomizing Buffer
- Derandomizing Buffer Control
- Readout Control
  - 1, 2, 3 Bunch crossings per Trigger
  - Optional Bunch crossing Reuse
- Trigger Counter

Simulation and Synthesis for FPGA and ASIC

# Summary



- OTISDLL1.0
  - Lock Range 30...50 Mhz
  - Clock, Hit Signals differential
  - DNL 0.79 Bins @40MHz
  - Problems:
    - cross talk from MUX
    - Guard Ring cut needed
- MEMORY
  - Functional Test successful
  - Timing within specification
- CONTROL ALGORITHM
  - Logic synthesizable for FPGA and ASIC
  - Tests on FPGA are in progress

# Next steps



- **DLL:**
  - Simultaneous operation of MEMORY and DLL (Power consumption, cross talk → DNL etc.)
  - Guard-Ring cut to reduce noise from MUX
- **Derandomizing Buffer:**
  - Timing (Beetle SR Test chip)
- **CONTROL ALGORITHM:**
  - Ongoing tests with FPGA
  - Design for Test:
    - Memory Self test
    - Implementation of external memory access
- **Fast serial link via GOL-chip**

# Future Steps



- Specification until October 2001
- Submission of first complete OTIS prototype in February 2002